

Search Notes

Application/Control No.

10/537,372

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

DIEM ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	E21.32, 678, 701 & 417	11/25/2007	C.C.
438	106	11/25/2007	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	11/25/2007	C.C.